

LIST OF REFERENCES CITED BY APPLICANT
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ATTY. DOCKET NO.:

4717-8500

APPLICATION SERIAL NO.:

10/764, 289

APPLICANT:

Bruno GHYSELEN et al.

FILING DATE:

January 23, 2004

GROUP:

2812

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*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
<i>Dle</i>	AA	5,882,987	3/1999	Srikrishnan	438	458	
	AB	6,284,628 B1	9/2001	Kuwahara et al.	438	459	
	AC	6,306,729 B1	10/2001	Sakaguchi et al.	438	458	
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	AF	6,468,923 B1	12/2002	Yonchara et al.	438	761	
<i>Dh</i>	AG	2002/0072130 A1	6/2002	Cheng et al.	438	10	

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		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
<i>Dle</i>	AH	EP 0 955 671 A1	11/1999	Europe			X	
	AI	EP 1 039 513 A2	9/2000	Europe			X	
	AJ	EP 0 926 709 A2	6/1999	Europe			X	
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	AL	EP 0 849 788 A2		Europe			X	
	AM	WO 01/11930 A2	2/2001	PCT			X	
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OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)

<i>Dle</i>	AO	L. J. Huang et al, "SiGe-on-insulator prepared by wafer bonding and layer transfer for high-performance field-effect transistors", Applied Physics Letters, Vol. 78, No. 9, pp. 1267-1269 (2001)
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	AQ	

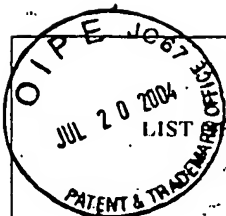
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